04DA3-347

RoHS Compliance

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SPECIFICATIONS

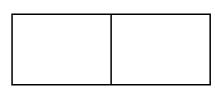
Messrs.	Approved by

Product	CRYSTAL UNIT
Type of Holder	CFS-206
Nominal Frequency	32.768 kHz
Customer's Parts Number	
Our Parts Number	CFS-20632768DZVB

Sales CITIZEN FINETECH MIYOTA Co.,LTD. Crystal Devices Department.

Manufacturer 4107-5,MIYOTA,MIYOTA-MACHI,KITASAKU-GUN,NAGANO,389-0295,JAPAN

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Revision History

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Record		Page	Section		Prepared				
Revision number									
1 st	2014/5/15								

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1. Scope

This document contains specifications for the crystal unit to be supplied by CITIZEN FINETECH MIYOTA Co.,LTD.

- 1.1 If something defined ambiguously or undefined in document happened, the customer and CITIZEN FINETECH MIYOTA would discuss and take necessary steps by mutual consent.
- 1.2 Product test data can't be attached to this document.

 The contents except Electrical Specifications in specifiations are subject the change without notice.
- 1.3 This product is not authorized for use as a critical component in life support devices or systems.

2. Electrical Specifications

2.1 Nominal Frequency 32.768 kHz

2.2 Operating Temperature Range $-20 \sim +70^{\circ}\text{C}$

2.3 Storage Temperature Range $-40 \sim +85^{\circ}\text{C}$

2.4 Frequency Tolerance ± 20 ppm Max. at 25° C

2.5 Frequency Tolerance over Turnover Temp.;25±5°C

Operating Temperature Range Temp.Coefficient:-0.034 \pm 0.006ppm/ $^{\circ}$ C²

2.6 Equivalent Series Resistance $35k\Omega$ Max.at 25° C

2.7 Insulation Resistance 500M Ω Min./DC100V \pm 15V

2.8 Shunt Capacitance 1.20pF Typ.

3. Test Conditions

3.1 Load Capacitance 8.0pF

This Load Capacitance has been fixed on customer's

request.

3.2 Level of Drive 1µW Max.

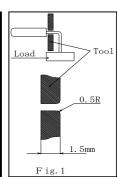
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4. Mechanical and Environmental Tests

	Test Name Test Conditions C				
1.M	echanical Tests				
1-1	Shock	Drop 3 times from the height of 75 cm onto hard wooden board with thickness of 3 cm.	A		
1-2	Vibration	Vibration Frequency: 10~500 Hz, 1.5mm, full wave, or acceleration 10G,			
		Cycle: 1.5 minutes, Direction: X.Y.Z.	A		
		Time: 2 hours in each direction, for 6 hours in total.			
1-3	Lead Pull	Weight: 1.0kg, Time: 30±5 seconds.	A•C		
1-4	Bending	Weight: 0.5kg, Bending Angle: 90 degrees, Bending Count: 2 times. (See Fig.1)	A•C		
	strength				
1-5	Solderability	After applying RMA flux, dip in solder. Dipping Time: 5±0.5seconds.			
		Soldering Temperature : 230±5 °C.	D		
		Dipping Depth: 2 mm from the edge of terminals of samples.			
1-6	Resistance to	Dip in solder. Dipping Time: 10±0.5 seconds.			
	Soldering Heat	Soldering Temperature : 260±5 °C.	В		
		Dipping Depth: 2mm from the edge of lead-wires of samples			
1-7	Sealing Tightness	Leak rate shall be measured by using Helium Leak Detector.	Е		
2. I	Environmental Te	sts	•		
2-1	Storage In	Expose the sample in an inoperative mode to 240 hours at -40°C.	A		
	Low Temperature				
2-2	Storage In	Expose the sample in an inoperative mode to 240 hours at +85°C.	В		
	High Temperature				
2-3	Humidity	Expose the sample in an inoperative mode to 240 hours at +65°C, and 95%RH.	В		
2-4	Thermal Shock	Subject the sample to 5 temperature variation cycles at -40°C for 30 minutes and	A		
		+100°C for the next 30 minutes in each cycle.			

Criteria

Criteria No.	Criteria
A	Any variation between the pre- and post-test frequencies shall remain within
	±5ppm. The equivalent series resistance shall remain within its specified
	tolerance range after the post-test.
В	Any variation between the pre- and post-test frequencies shall remain within
	±10ppm. The equivalent series resistance shall remain within its specified
	tolerance range, after the post-test.
C	After each test, no visible damage, nor the hermetic seal break down.
D	At least 90% of each dipped area shall be covered by fresh solder.
Е	1×10^{-2} µPa·m ³ /s Max.

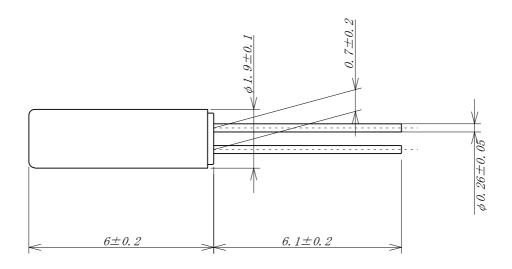


% Measurements should be taken place at 25±2°C after each test, the samples shall be left at 25°C for one to two hours.

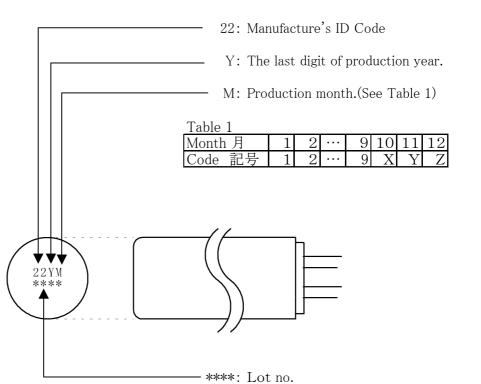
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5. Dimensions

(unit:mm)



6. Marking Standards



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7. Packing

(1)Inner Carton

[Bar Code Label Item]

- * Customer P/N
- * Lot.No.
- * CITIZEN P/N
- * Ctl No

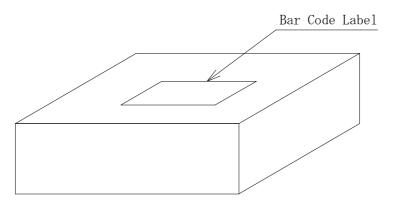
* Date Code yy: The last 2 digits of shipment year

ww: Week Code

* Quantity

* Country Code CN=China

【Inner Carton for 10000pcs】



(2)Quantity

1000pcs/bag at max. 10000pcs/carton (10 bags)

8. Storage Condition

8.1 Storage Condition Temperature $5\sim35^{\circ}\text{C}$

Humidity $45\sim75\%$

8.2 A period of guarantee Twelve months

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9. Manufacturer

MASTER CROWN ELECTRONICS (WUZHOU) LIMITED. No3 BUILDING 137.XINXING ER ROAD, WUZHOU, GUANGXI, CHINA

TEL: +86-774-3863148

Country of Origin: CHINA

* This manufacture is under the control of CITIZEN FINETECH MIYOTA CO.,LTD.

10. Ozone Depleting Substance (ODS)

This Product doesn't use the class I ODS at any of production processes, and component parts.

11. Precautionary Statement

11-1 When dropped by mistake

The crystal products are designed and manufactured to resist physical shocks. However,in the event the crystal is subjected to excessive impact such as being dropped onto the floor or giving shocks during mounting. Need to make sure its satisfactory performance before using it.

11-2 Soldering and Mounting

- (1) Lead wires should be soldered within 3 seconds with the iron heated to a temperature no higher than 380degC.
- (2) In solder-dip mounting ,it should be within 10 seconds with a temperature no higher than 260degC.

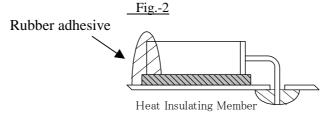
And beware not to heat the whole crystal unit in the dip mounting process.

Mounting in upright bearing is recommendable (prevent heat conduction directly to the body of a crystal unit.)

(Such as by isolating the unit body from the board with a heat insulating member, see Fig.2.)

(3) Soldering on the body of the cylinder type crystal unit must be strictly avoided due to deteriorate the characteristics or damage the products.

Rubber adhesive is recommended. (See Fig.-2)



(4) Heating the whole crystal unit, for example, in a reflow oven may deterioration of the performance. Because the holder is quite small and it is sealed by solder material with press sealing so that such reflow process not allowed to be proceeded.

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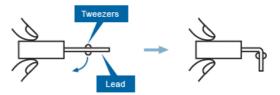
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(5) Please (3.0mm recommendation) separate, and bend it as much as possible with a treatment device when it lays in the substrate of the crystal oscillator and it installs it. Please avoid bending it directly from the lead wire root.

- (6) Please do not shave off the solder plating of the lead wire when you bend the lead wire of the crystal oscillator.
- (7) Lead forming by hand when you do the following please
 - * Hand with a sealed tube
 - * With fine forceps and bending.

0.5mm position is bending over, bent by hand and if you get into that work, with minimal possible that the 3.0mm hermetically recommended that bend over the place.

* 90 degree bend while holding the lead with tweezers. At this time, please note that you do not have enough pull to lead.



11-3 Cleaning

- (1) Crystal products may be affected and destroyed at worst by ultrasonic cleaning. Please be sure to check if your cleaning process affects any damage to crystal products prior to use.
- (2) Some kind of cleaning fluid may cause any damage to crystal products . Please be sure to check suitability of the cleaning fluid in advance.

11-4 Storage

Storage of Crystal products under higher temperature or high humidity for a long term may affect frequency stability or solderability. Please store the Crystal products under the normal temperature and humidity without exposing to direct sunlight and dew condensation, and avoid the storage of Crystal products for more than 6 months, and mount them as soon as possible after unpacking.

11-5 Replacement

If the defect is caused by our company within one year from the delivery time, we provide the replacements with free of charge.

OC Chart	Overta Caretal Lin					A 1	C1 1 1	l n
QC Chart	Quartz Crystal Un	iit	-	November-11-2013 水晶部 技術課)	Approved	Checked	Prepa
			-	evices Div. Product act Engineering Se	-	想		(#
					管理仕様			
工程図 Flowchart			工程名 Process Name	Control Specifications		抜取	記録 Record	
		1	受入検査	Control Item 仕様	Control Criteria 納入仕様書	Sampling 品質受入	検査表	
水晶片	START		(水晶片)	Specification	Specifications	検査基準書		
Crystal Element	JI/IKI		Acceptance			Quality	Inspection	
Ĭ			Inspection (Crystal Element)			Acceptance Inspection	(Crystal E	hemen
						Standard		
$\langle 1 \rangle$		2	蒸着 Evaporation	湿度 Humidity	作業指示書 Manufacturing	_	記録紙 Printed Da	nt o
$\overline{}$			Lvaporation	真空度	Process		稼動表	ıa
				Pressure	Instruction	_	Operating	
気密端子 Jeametically Sealed Base	2			トータル膜厚 Total Thickness		_	推移グラフ Change Gr	
✓ Sealed Base								
		3	周波数粗調整	周波数	作業指示書	抜取	チェックシ	
4	3		Frequency Rough Tuning	Frequency 外観	Manufacturing Process	Sampling 抜取	Check She 送品検査	
				Appearance	Instruction	Sampling	Process In	
			≖ 1 1 1 1 1 1 1	71.1关	(d) 1 (1 1 1 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2	口師並ュ	Sheets	
		4	受入検査 (気密端子)	仕様 Specification	納入仕様書 Specifications	品質受入 検査基準書	検査表 Inspection	Sheet
			Acceptance	promound	promound in	Quality	mopeouton	Diloco
	5		Inspection			Acceptance		
			(Heametically Sealed Base)			Inspection Standard		
		5	組立	外観	作業指示書	全数	チェックシ	
封止管	6		Assembly	Appearance	Manufacturing Process	100%	Check she	ets
Cap ▽					Instruction			
		6	周波数微調整	周波数	作業指示書	抜取	分布図	
8	7		Fine Tuning	Frequency	Manufacturing Process	Sampling	Distributio	n Cha
,					Instruction			
L		7	アニール	真空度	作業指示書	_	チェックシ	
			(半完成品) Annealing	Pressure 温度	Manufacturing Process		Check She チェックシ	
	9			Temperature	1100000	_	Check She	eets
				時間 Time		_	チェックシ	
		8	受入検査	Time 仕様	納入仕様書	品質受入	Check She 検査表	ets
	10		(封止管)	Specification	Specifications	検査基準書		Sheet
			Acceptance Inspection			Quality Acceptance		
			(Cap)			Inspection		
	11		_	古亦声	/b*₩~==	Standard	-t -:	- 1
		9	封止 Sealing	真空度 Pressure	作業指示書 Manufacturing	_	チェックシ Check She	
			-5	寸法		抜取	Xbar-R管理	理図
				Dimension		Sampling	Xbar-R Co Chart	ontrol
	12	10	印刷	印刷外観	作業指示書	抜取	チェックシ	<u>-</u>
			Marking	Marking	Manufacturing	Sampling	Check She	ets
				Appearance	Process			
	13	11	ベーキング	温度	作業指示書	_	チェックシ	
	13		Baking	Temperature 時間	Manufacturing Process		Check She 作業履歴	
				Time	Instruction	_	TF耒腹症 Manufactu	
	14	4.0	帝与射 山小	赤 层丛母 10	/b*₩~==	△₩ -	Record	1
		12	電気特性検査 Electrical	電気的特性 Electrical	作業指示書 Manufacturing	全数 100%	チェックシ Check She	
			Characteristics	Characteristics	Process	-		-
		10	Inspection 出費判定	電気的特性	Instruction 出荷判定基準書	抜取	出荷判定原	北海士
	END	13	出荷判定 Delivery	电気的特性 Electrical	出何判正基準書 Delivery	抜取 Sampling	出何判正》 Delivery	以隕衣
			Judgment	Characteristics	Judgment		Judgment :	Sheets
					Standard			
		14	梱包	個数	梱包仕様書			
			Packing	Quantity	Packing	_	-	-
			1	I	Specification		<u>I</u>	